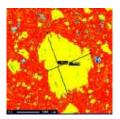
技術情報 Technical Information

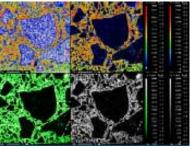
Image Processing Techniques for Mapping

JXA-8100/8200 series: Versatile visualization

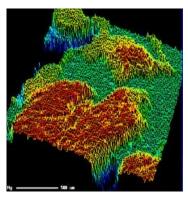


Map Analysis/Metrology

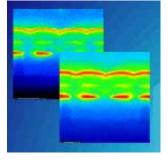
Size of Si particle measured from an X-ray image in the Map Analysis program



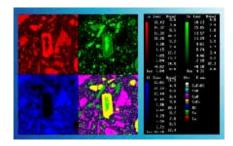
Pseudo Colors and Grayscale X-ray image of Ca in concrete in pseudo colors and gray scale



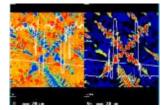
Birdseye View 3D mesh display of Mg intensities represented as height



Smoothing X-ray image of an IC cross section smoothed for enhanced S/N ratio

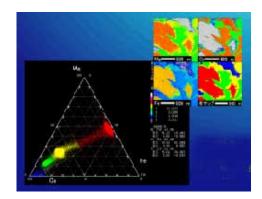


Composite Mapping
Single color maps of Fe, Ca, and Al of mineral
grains and the resulting RGB phase map

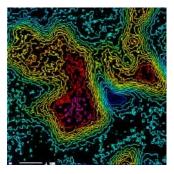


Line Profiling
Overlapping X-ray line images and line profiles in
the Map Analysis program

Electron Probe Micro Analyzer



Phase Analysis
Compositional plot of the Mg, Fa, and Ca in X-ray
map data and the resulting phase map
(Optional software)



Contour Display
A contour display of the X-ray image of W in a tool steel

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